

QUALIFICATION RESULTS FOR 8-LFCSP			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
Highly Accelerated Stress Test (HAST)*	JEDEC <i>JESD22-A110</i>	231	Pass
Temperature Cycle (TC)*	JEDEC <i>JESD22-A104</i>	231	Pass
Autoclave (AC)*	JEDEC <i>JESD22-A102</i>	231	Pass
High Temperature Storage Life (HTSL)	JEDEC <i>JESD22-A103</i>	77	Pass
Solder Heat Resistance (SHR)*	JEDEC/IPC <i>J-STD-020</i>	33	Pass
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JESD22-C101</i>	3/voltage	Pass ±1250V

*Preconditioned per JEDEC/IPC J-STD-020

QUALIFICATION RESULTS FOR 16-LFCSP			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
Highly Accelerated Stress Test (HAST)*	JEDEC <i>JESD22-A110</i>	231	Pass
Temperature Cycle (TC)*	JEDEC <i>JESD22-A104</i>	231	Pass
Autoclave (AC)*	JEDEC <i>JESD22-A102</i>	231	Pass
High Temperature Storage Life (HTSL)	JEDEC <i>JESD22-A103</i>	77	Pass
Solder Heat Resistance (SHR)*	JEDEC/IPC <i>J-STD-020</i>	33	Pass
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JESD22-C101</i>	3/voltage	Pass ±1250V

*Preconditioned per JEDEC/IPC J-STD-020